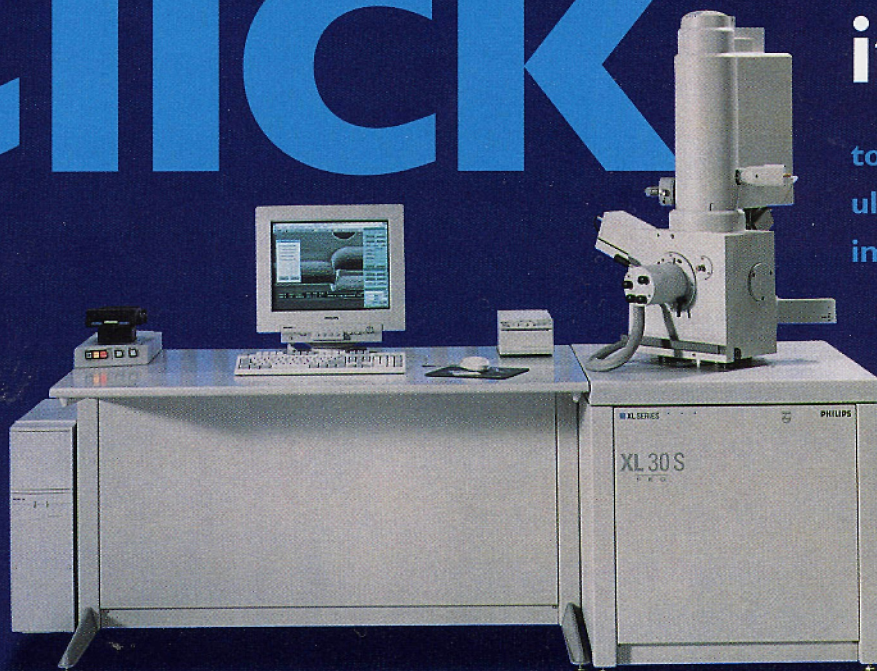


Click that's all it takes

to go from high to
ultra-high resolution
imaging



Navigate your sample with low-magnification TV-rate imaging. Determine where to zoom in. Then click the mouse button, and the XL30 S FEG scanning electron microscope with its unique Hexalens automatically switches to ultra-high resolution mode. Your sample stays in view, and you get an amazingly detailed image of the uncoated specimen.

High magnification, low kV

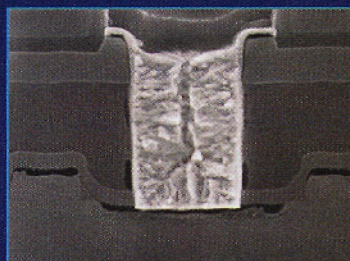
The XL30 is the SEM for high-magnification, low-kV imaging in materials research, life sciences and semiconductors. Low kV means there's no need for coatings that could damage or hide the very features you are interested in.

Dual-mode Hexalens

With its six-coil construction, the Hexalens column provides dual-mode operation. The standard 'field-free' mode, with its enhanced depth of focus and topography, is ideal for initial navigation. Switch to the ultra-high resolution 'immersion' mode and you get an altogether sharper, more detailed and brighter image, even for highly tilted samples at low kV.

The XL30 detects both secondary electrons (SE) and backscattered electrons (BSE) below 1 kV, and at TV-rate. It allows you to change between SE and BSE detection to examine specific features of a sample.

Contact us for more about the XL30 S FEG's highlights.



Semiconductor cross-section
of W-plug at 50,000x

HEXALENS

The unique Hexalens on the XL30 S FEG allows you to switch from standard high-resolution mode to an ultra-high resolution mode across the instrument's full kV range, even below 1 kV! Materials like plastics, polymers and ceramics need no conductive metal coating.

FEI Company

7451 N.W. Evergreen Parkway
Hillsboro, Oregon 97124-5830
Tel. 503 640 7500
Fax 503 640 7509
Email: marcom@eo.ie.phillips.nl
Website: www.feic.com



PHILIPS

Let's make things better.

You Can Afford This!

**PC
SEM**

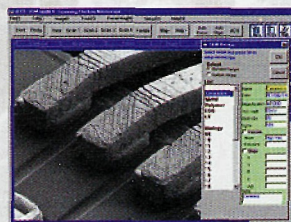
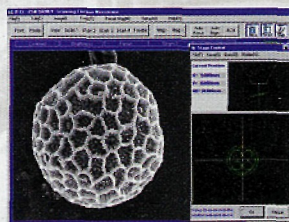
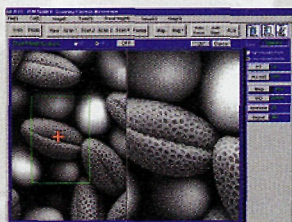
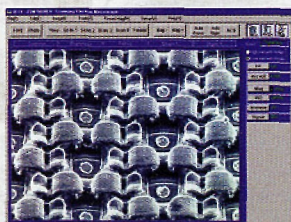


**That's right,
you can get the
quality of a JEOL
SEM now for under
\$80,000!**

**If leasing this means
around \$1,500 per
month.**

JSM-5600 & JSM-5600LV

Multi-Purpose and Low Vacuum Scanning Electron Microscope



All screens are clear and simple allowing easy system management and image optimization.

- ▶ **Based on a Simple PC Interface.**
- ▶ **Intuitive Operation with a Mouse Alone.**
- ▶ **No Nonsense Transition Between Conventional and Low Vacuum Modes.**
- ▶ **Built-in DTP System Allows Quick and Easy Report Generation and Printing.**
- ▶ **A Special High Sensitivity Detector Allows High Image Quality In All Modes.**

The new JSM-5600 and JSM-5600LV Scanning Electron Microscope was designed from the ground up as a PC SEM. This means that it can be controlled completely and efficiently from only the keyboard

and mouse. Keeping in mind the wide variety of preferences for controlling various aspects of an SEM we have also included an optional knobset for multitasking and fine control. You choose.

If you are currently in the market for a high end conventional or low vacuum SEM and need to combine state-of-the-art electronics with the versatility of computer control, we would like to invite you to come to our Applications Facility so that we can prove to you that it really is "As Easy As It Looks".

JEOL USA, Inc., 11 Dearborn Road, Peabody, MA 01960
Tel: 978/535-5900 • Fax: 978/536-2205
Email: eod@jeol.com • WEB: <http://www.jeol.com>

JEOL

Circle Reader Inquiry #3